Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/735,560	WON, NARA
Examiner	Art Unit
JOHN J. LEE	2618

	SEARCHED					
Class	Subclass	Date	Examiner			
455	550.1,333 551,552.1 553.1,334 558	12/11/2008	J.L			
455	554.2,73	12/11/2008	J.L			
455	90.1,108	12/11/2008	J.L			
455	142,252.1	12/11/2008	J.L			
455	41.2,66.1	12/11/2008	J.L			
438	63	12/11/2008	J.L			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
455	550.1,333	12/16/2008	J.L		
455	551,552.1	12/16/2008	J.L		
455	252.1,334	12/16/2008	J.L		
Interference and Inventor search		12/16/2008	J.L		

SEAR( (INCLUDING SE	CH NOTES	RATEGY	)
		DATE	EXMR
EAST	12	2/11/2008	J.L